

FIG. 2

TEST ON THREE MEMORIES COUPLED TO A SINGLE SEQUENTIAL BIST
CONTROLLER USING THREE SEPARATE IDLE PERIODS

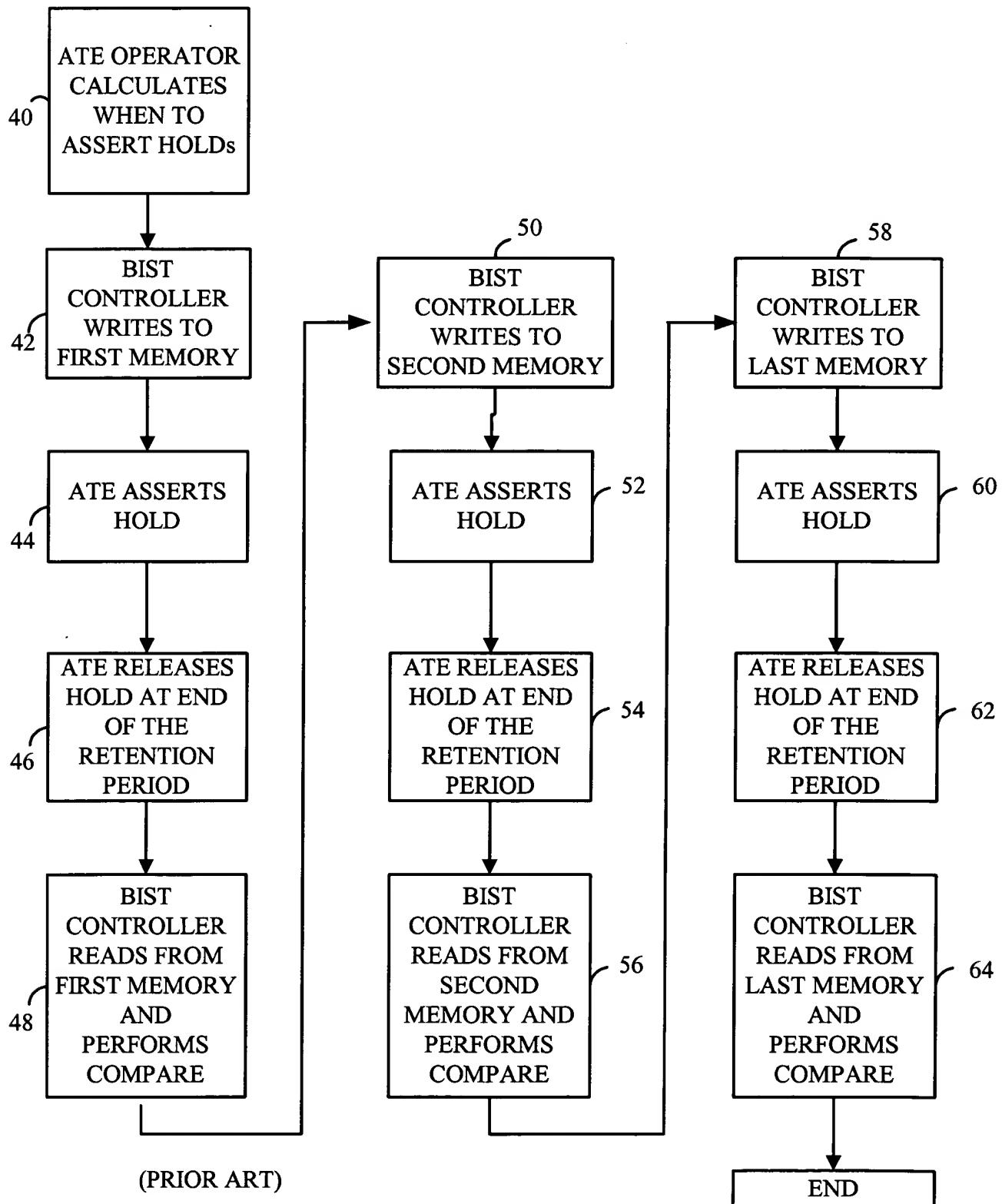


FIG. 3
N MULTIPLE BIST CONTROLLERS WITH SINGLE SYNCHRONIZE AND RESUME PINS

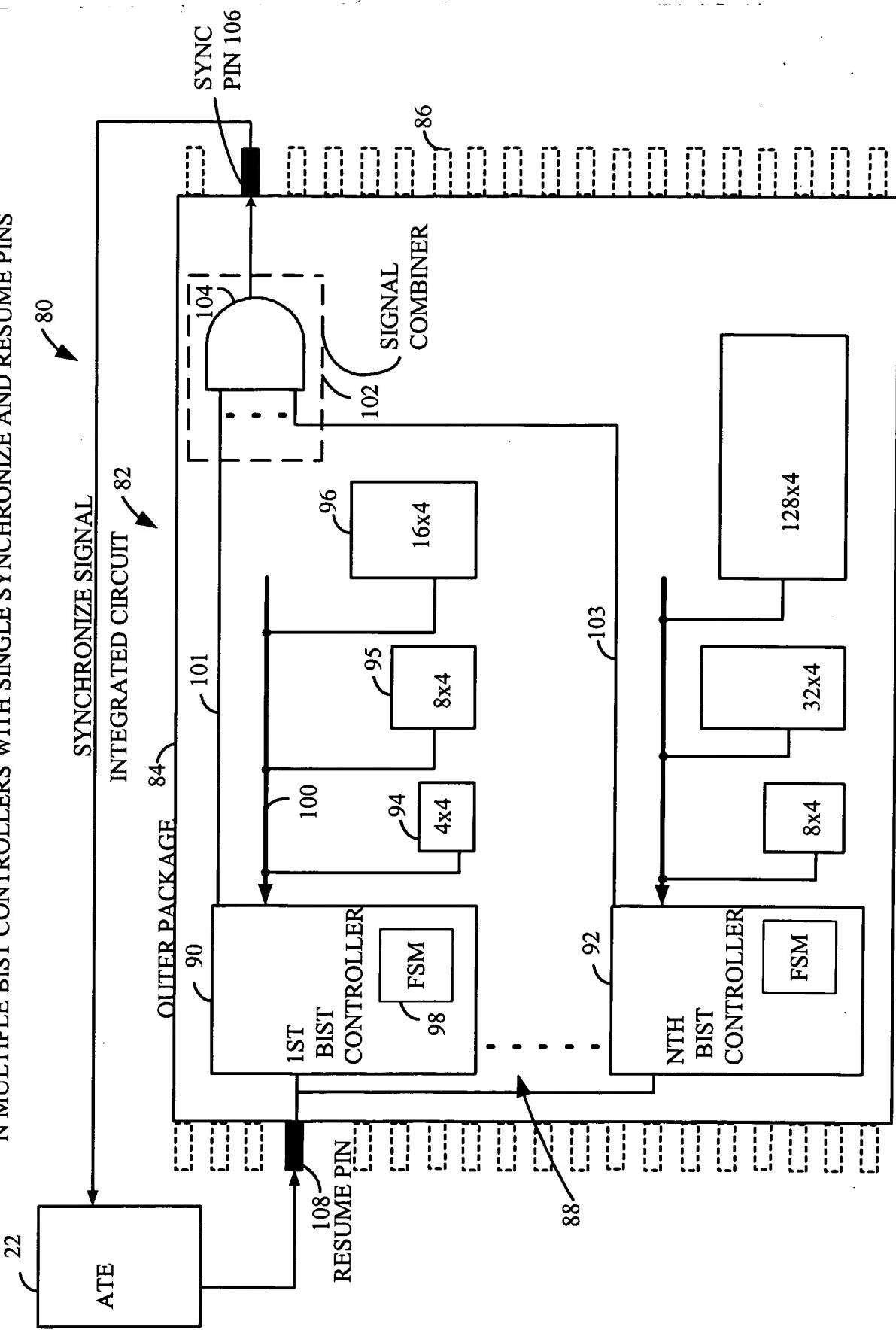


FIG. 4

TEST OF MEMORIES WITH MULTIPLE PARALLEL BIST CONTROLLERS USING SYNCHRONIZATION STATE

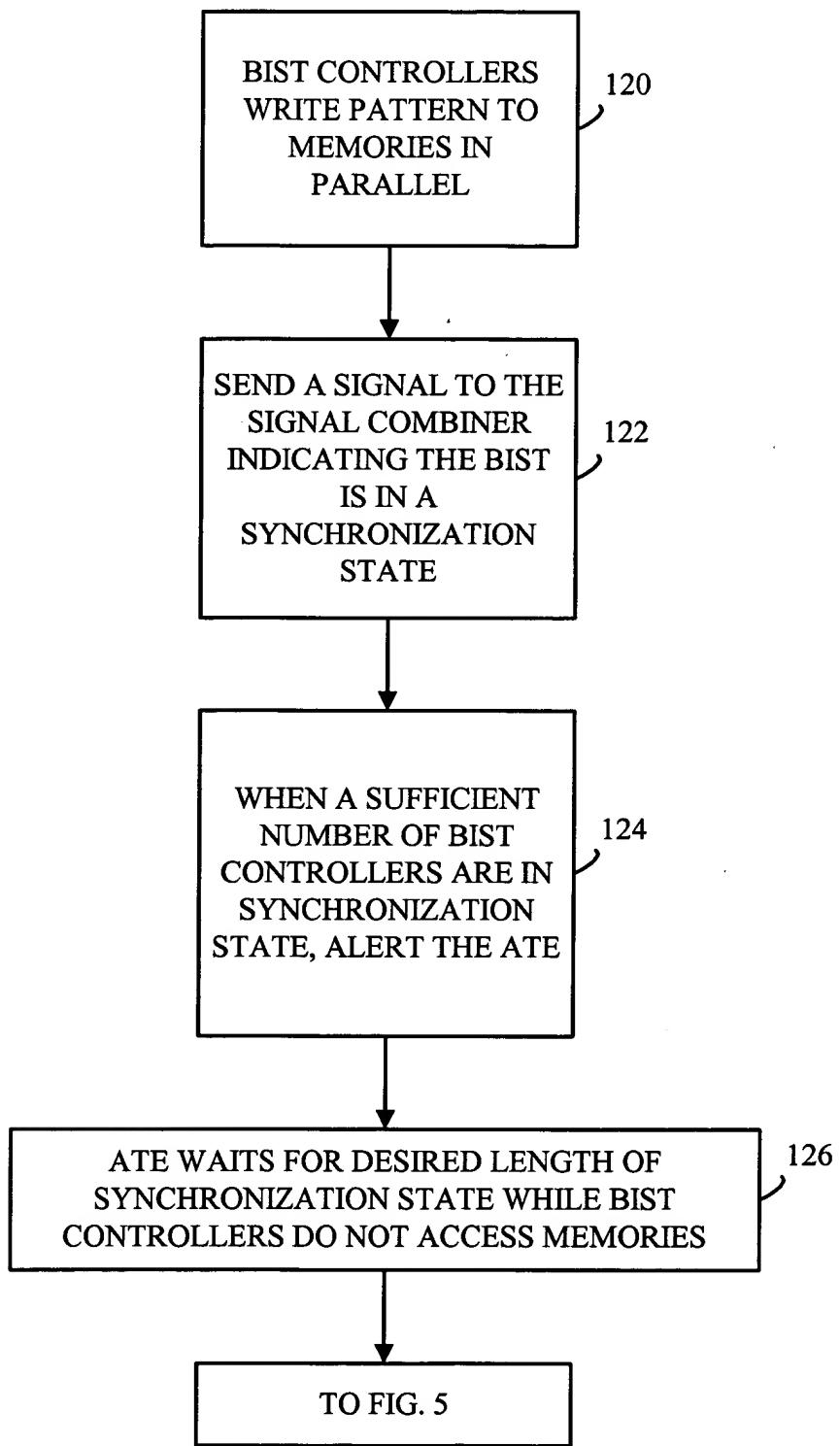


FIG. 5

TEST OF MEMORIES WITH MULTIPLE PARALLEL BIST
CONTROLLERS USING SYNCHRONIZATION STATE (CONTINUED)

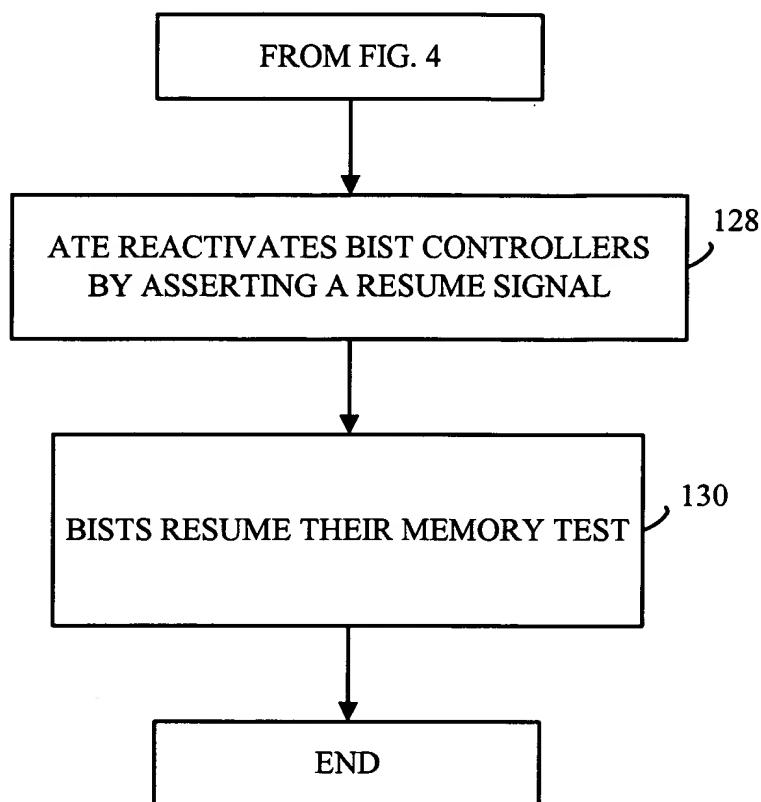
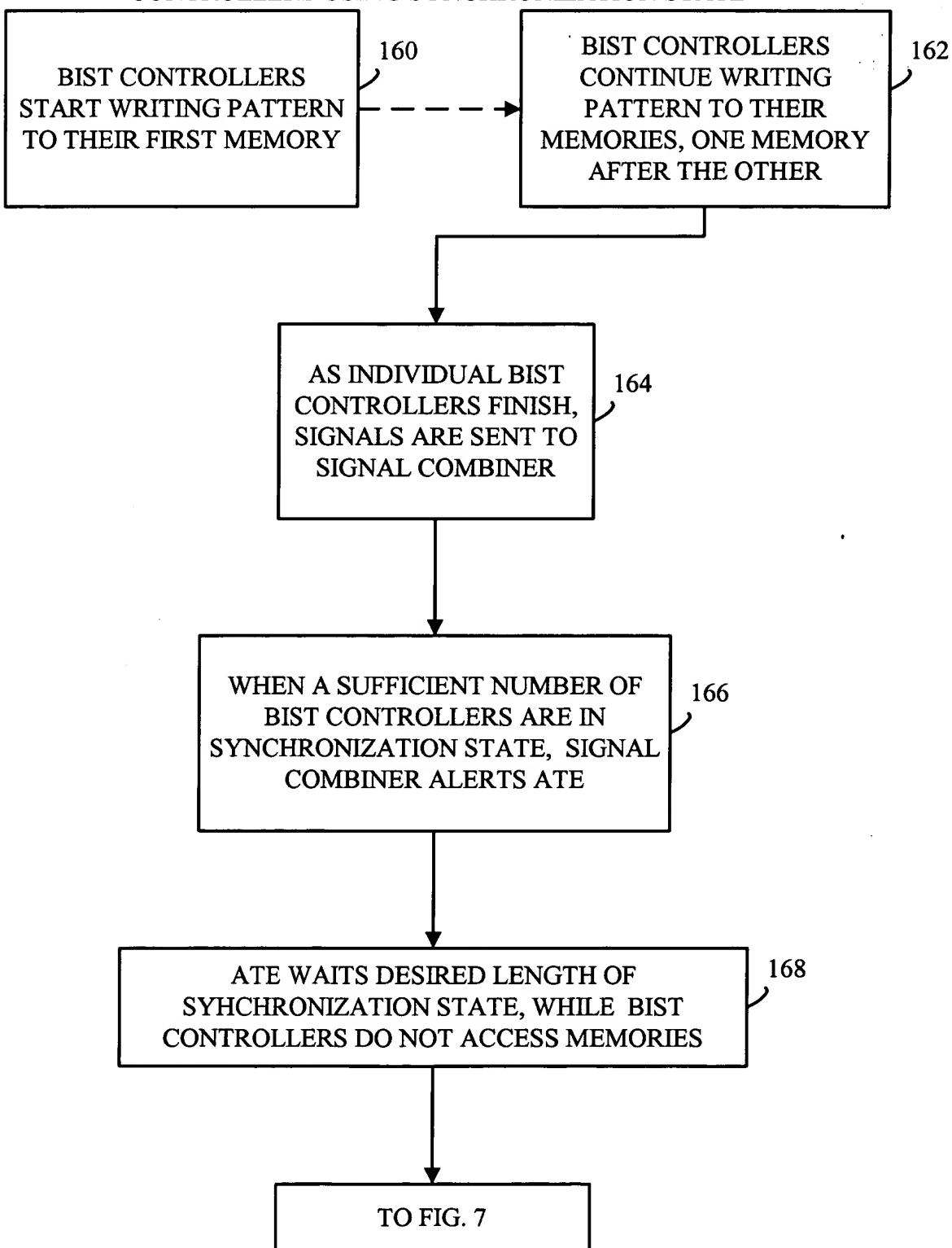


FIG. 6

TEST OF MEMORIES WITH MULTIPLE SEQUENTIAL BIST CONTROLLERS USING SYNCHRONIZATION STATE



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FIG. 7

TEST OF MEMORIES WITH MULTIPLE SEQUENTIAL BIST CONTROLLERS USING SYNCHRONIZATION STATE (CONTINUED)

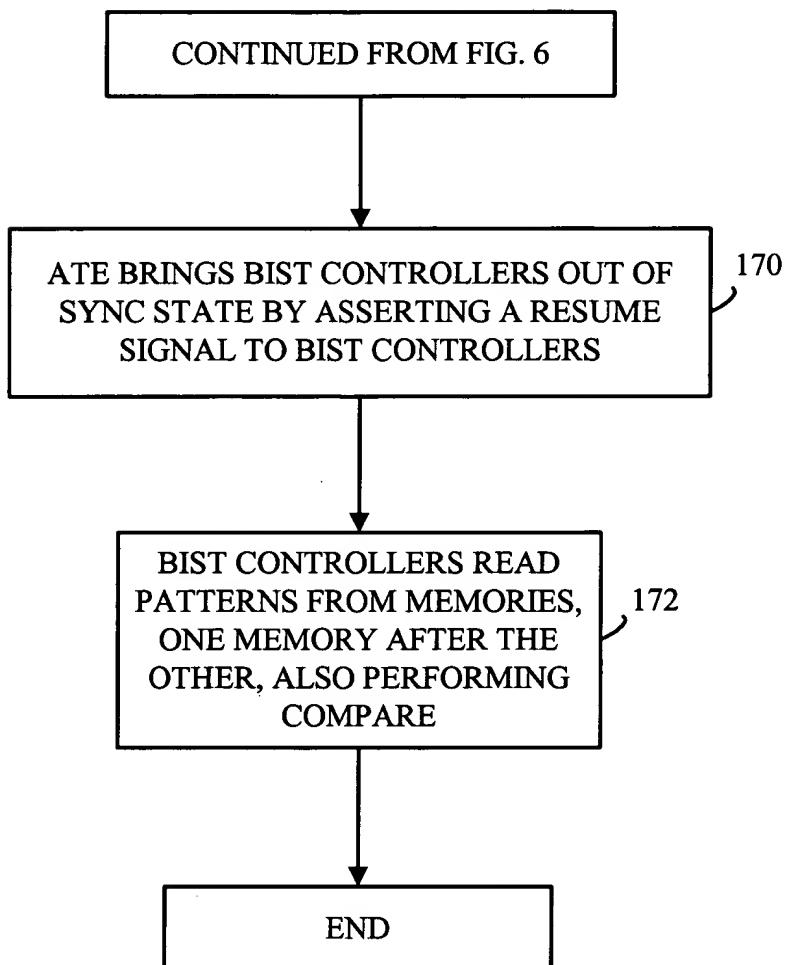


FIG. 8—BIST CONTROLLER GENERATOR

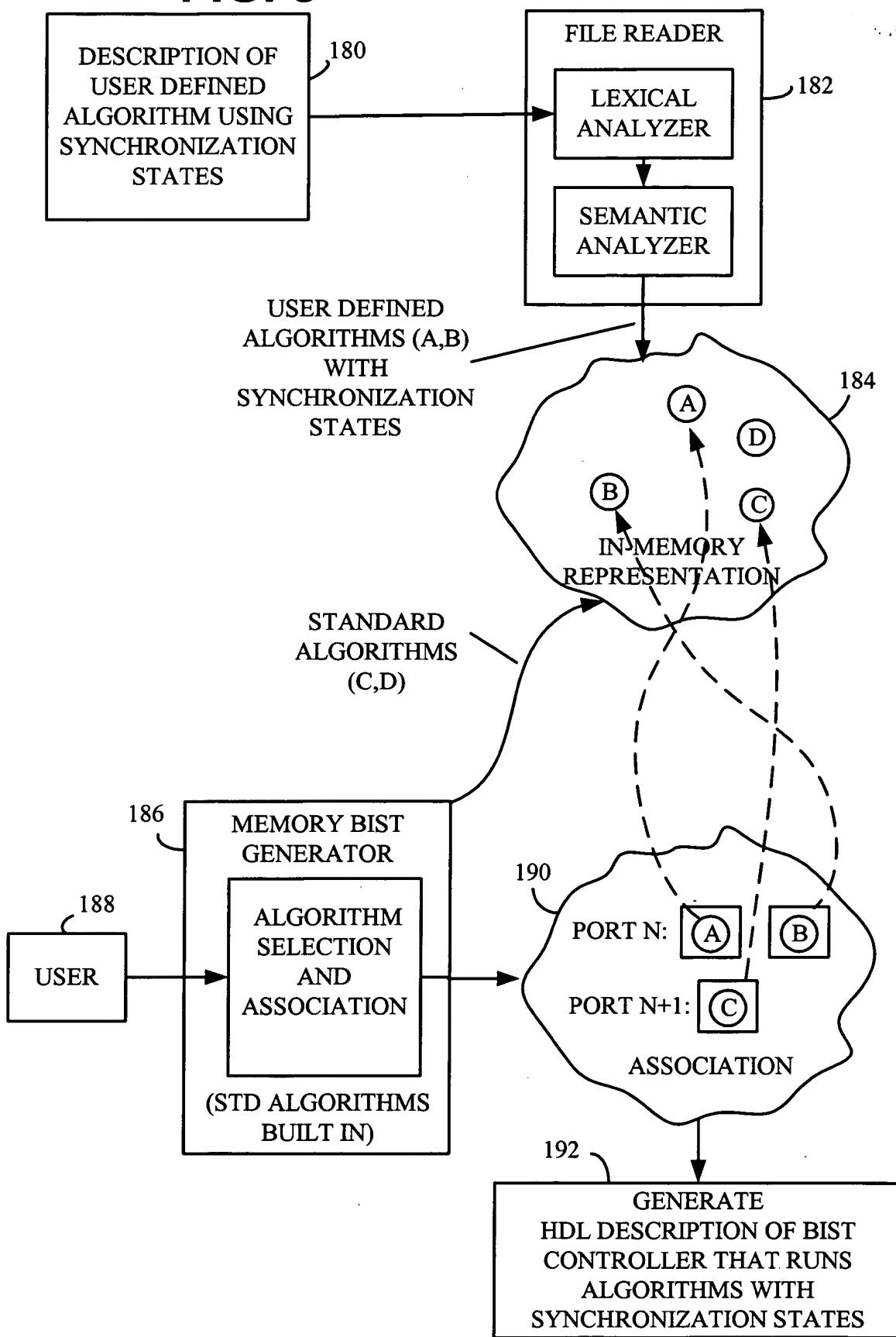


FIG. 9

GENERATING A BIST CONTROLLER THAT RUNS USER
DEFINABLE ALGORITHMS WITH SYNC KEYWORD

